

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/805,890	NALLAN ET AL.	
Examiner	Art Unit	
Binh X. Tran	1765	

	SEARCHED				
Class	Subclass	Date	Examiner		
216	58	11/9/2005	ВТ		
216	67	11/9/2005	ВТ		
216	68	11/9/2005	ВТ		
438	722	11/9/2005	ВТ		

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Search keywords and inventors' name using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	11/9/2005	ВТ
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